Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: **TB1811-01** DATE: **7-Nov-2018**

Product Affected: F1912NCGI, F1912NCGI8
P9320S-2AHGI, P9320S-2AHGI8

Date Effective: **7-Feb-2019**

MEANS OF DISTINGUISHING CHANGED DEVICES:

☐ Product Mark
☐ Back Mark
☐ Date Code
■ Other

Traceability to the test location is maintained by IDT and available on request

Contact: IDT PCN DESK
E-mail: pcndesk@idt.com

Attachment: ■ Yes ☐ No

Samples: Please contact your local sales representative for sample request.

DESCRIPTION AND PURPOSE OF CHANGE:

☐ Die Technology
☐ Wafer Fabrication Process
☐ Assembly Process
☐ Equipment
☐ Material
☐ Testing
■ Manufacturing Site
☐ Data Sheet
☐ Other

This notification is to advise our customers that IDT is adding Sigurd, Taiwan as an alternate facility for Test process for F1912NCGI, F1912NCGI8 and P9320S-2AHGI, P9320S-2AHGI8 that are presently tested at IDT Penang, Malaysia and SFA, Korea respectively.

Attachment I details the change.

RELIABILITY/QUALIFICATION SUMMARY:

There is no expected change to the product quality or reliability performance. Please refer to Attachment I for Electrical correlation data.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.
IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: ______________________

☐ ***Approval for shipments prior to effective date.***

Name/Date: ______________________

E-Mail Address: ______________________

Title: ______________________

Phone# /Fax# : ______________________

CUSTOMER COMMENTS: ______________________

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: ______________________ DATE: ______________________

ATTACHMENT I - PCN # : TB1811-01

PCN Type:	Manufacturing Site - Alternate Test Location
Data Sheet Change:	None

Detail Of Change:

This notification is to advise our customers that IDT is adding Sigurd, Taiwan as an alternate facility for Test process for F1912NCGI, F1912NCGI8 and P9320S-2AHGI, P9320S-2AHGI8 that are presently tested at IDT Penang, Malaysia and SFA, Korea respectively.

This change will allow IDT the flexibility to ship from either facility and will provide the increased capacity, flexibility and shorter lead time to meet market demand.

There is no change in the Test processing flows. Load boards are the same at both qualified facilities. IDT has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the test facilities with no change to the test coverage.

If you require samples to conduct evaluations, please contact your local sales representative to acknowledge this PCN and request samples.

ATTACHMENT I - PCN # : TB1811-01

Qualification Information and Qualification Data:

Electrical Test Correlation Results, F1912NCGI, F1912NCGI8

Vehicle:	F1912ZA
Sample size:	10 good and 5 reject units tested by hand test 1453 good units correlation by handler

Description	Existing Test (IDT - IDT, Penang)	Alternate Test (Sigurd, Taiwan)
Tester Platform	J750	UltraFLEX
Test Program	F1912_FT_Rev02	F1912_UflexT8_Rev01
Test Site	Quad Site	Octal Site
Test Temperature	Ambient	Ambient
Test Correlation Results	100%	100%
Number of Good Units Correlated (Handler)	1453 units	1453 units
1453 good units datalog correlation	Passed	Passed
Number of Good Units (Hand Test)	10 units	10 units
10 good units datalog correlation	Passed	Passed
Number of Reject Units (Hand Test)	5 units	5 units
5 reject units datalog correlation	Passed	Passed

Electrical Test Correlation Results, P9320S-2AHGI, P9320S-2AHGI8

Vehicle:	P9320S-2AHGI
Sample size:	8 good units tested by hand test, 20 loop test correlation Wafer Sort Correlation (Production Pilot Lot)

Description	Existing Test (SFA, Korea)	Alternate Test (Sigurd, Taiwan)
Tester Platform	IFLEX	IFLEX
Test Program	IDTP9320S-2_CSP_Rev._1p00	IDTP9320S-2_CSP_Rev._1p00
Test Site	Octal Site	Octal Site
Test Temperature	Ambient	Ambient
Test Correlation Results	100%	100%
Number of Good Units Correlated (Hand Test)	8 units	8 units
8 good units datalog correlation	Passed	Passed
Number of Loop Test (Hand Test)	20 units	20 units
Gage datalog correlation	Passed	Passed
Wafer Sort Correlated (Production Pilot Lot)	11712 (SL04044 QVK547)	11719 (SL04376 QVK461)
Yield, Pareto and Distribution correlation	Passed Correlation	Passed Correlation